



Advanced Characterization Methods: Understanding the Structure and Functionality of Materials

IMPORTANT DATES

March 15:
On-line registration closes for
sensitive countries

MARCH 27:
Scholarship application deadline

APRIL 3:
Student scholarship
announcement

APRIL 16 (**extended**):
On-line registration closes for
non-sensitive countries

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Oak Ridge Chapter of ASM
International
Oak Ridge National Laboratory
Thermo Fischer Scientific Inc.
Hitachi HTA, Inc.

Registration Fee:
Regular \$120
Student \$30
Retiree \$40

APRIL 20-21, 2010

American Museum of Science and Energy (AMSE),
Oak Ridge, Tennessee

- The Oak Ridge Chapter of ASM International, in partnership with Oak Ridge National Laboratory is proud to organize *Advanced Characterization Methods: Understanding the Structure and Functionality of Materials*.
- The educational symposium is directed to the university, industry and government communities involved in materials science and engineering. *Advanced Characterization Methods* will focus on recent developments in materials issues related the structure/property relationships.
- April 20: Invited talks
- All attendees are invited to a reception, April 20, 6:30-8:30 p.m. at AMSE.
- Open House April 21: the attendees are invited to visit the characterization facilities at ORNL (sign-up required 35 days in-advance for foreign nationals).
- For more information, please contact Jane Howe, 865.241.9745 (howej@ornl.gov)
- For Registration:
http://www.ms.ornl.gov/ASM_ACM_Symposium/registration.shtml

Speakers

- Tim Nunney (Thermo Fisher Scientific) "From solar cells to fuel cells: advanced surface characterization with XPS"
- Mark Wall (Thermo Fisher Scientific) "Modern Raman Spectroscopy: Instrumentation and Applications"
- Xiaofeng Zhang (Hitachi HTA, Inc.) "Activating Materials in Transmission Electron Microscope"
- Denise McKay (Smith College) "Neutron Radiography Studies on PEM Fuel Cell Dynamics"
- Karren More (ORNL) "Understanding Catalyst using Aberration Corrected STEM"
- Jamil Clarke (Hitachi HTA, Inc.) "Applications in Materials Science Utilizing Advanced FIB+SEM"
- Don Baer (Pacific Northwest National Laboratory) "XPS Analysis of Nanomaterials"
- Xun-li Wang (ORNL) "In-situ study of microstructure evolution and mechanical behaviors using neutron scattering"
- Phillip Russell (Appalachian State University) "SEM- Much More Than Just Beautiful Images"